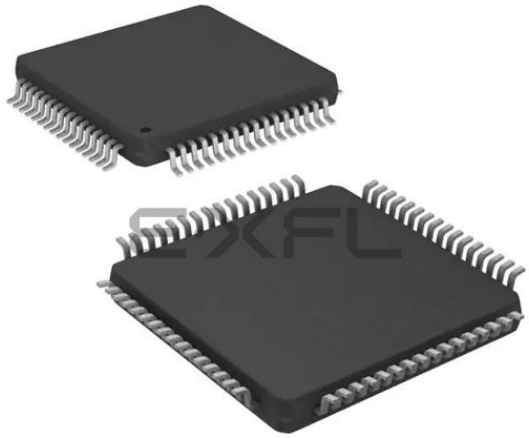


Welcome to E-XFL.COM

What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	AVR
Core Size	8/16-Bit
Speed	32MHz
Connectivity	I²C, IrDA, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, POR, PWM, WDT
Number of I/O	50
Program Memory Size	192KB (96K x 16)
Program Memory Type	FLASH
EEPROM Size	2K x 8
RAM Size	16K x 8
Voltage - Supply (Vcc/Vdd)	1.6V ~ 3.6V
Data Converters	A/D 16x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	64-TQFP
Supplier Device Package	64-TQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/atxmega192d3-anr

after reset, and the initial value is the highest address of the internal SRAM. If the SP is changed, it must be set to point above address 0x2000, and it must be defined before any subroutine calls are executed or before interrupts are enabled.

During interrupts or subroutine calls, the return address is automatically pushed on the stack. The return address can be two or three bytes, depending on program memory size of the device. For devices with 128KB or less of program memory, the return address is two bytes, and hence the stack pointer is decremented/incremented by two. For devices with more than 128KB of program memory, the return address is three bytes, and hence the SP is decremented/incremented by three. The return address is popped off the stack when returning from interrupts using the RETI instruction, and from subroutine calls using the RET instruction.

The SP is decremented by one when data are pushed on the stack with the PUSH instruction, and incremented by one when data is popped off the stack using the POP instruction.

To prevent corruption when updating the stack pointer from software, a write to SPL will automatically disable interrupts for up to four instructions or until the next I/O memory write.

After reset the stack pointer is initialized to the highest address of the SRAM. See Figure 7-2 on page 16.

6.8 Register File

The register file consists of 32 * 8-bit general purpose working registers with single clock cycle access time. The register file supports the following input/output schemes:

- One 8-bit output operand and one 8-bit result input
- Two 8-bit output operands and one 8-bit result input
- Two 8-bit output operands and one 16-bit result input
- One 16-bit output operand and one 16-bit result input

Six of the 32 registers can be used as three 16-bit address register pointers for data space addressing, enabling efficient address calculations. One of these address pointers can also be used as an address pointer for lookup tables in flash program memory.

19. RTC – 16-bit Real-Time Counter

19.1 Features

- 16-bit resolution
- Selectable clock source
  - 32.768kHz external crystal
  - External clock
  - 32.768kHz internal oscillator
  - 32kHz internal ULP oscillator
- Programmable 10-bit clock prescaling
- One compare register
- One period register
- Clear counter on period overflow
- Optional interrupt/event on overflow and compare match

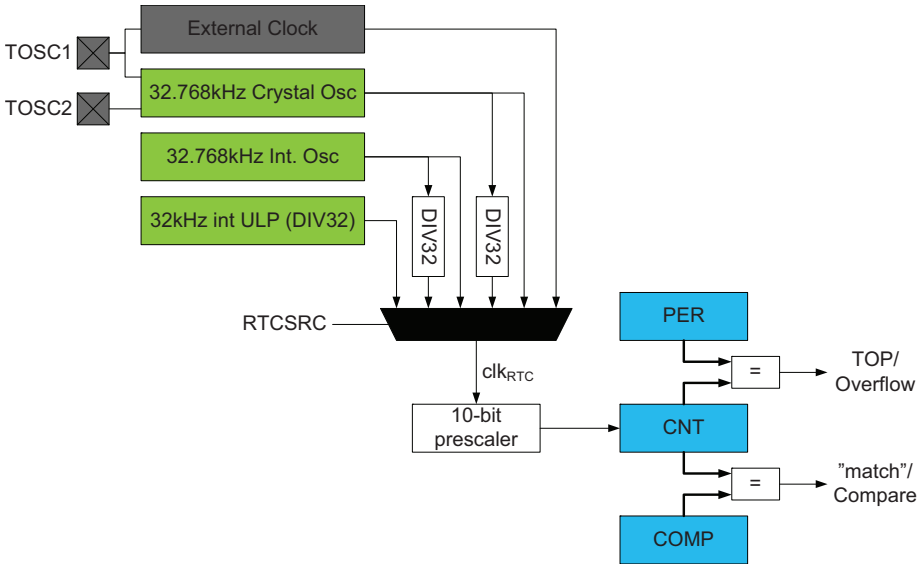
19.2 Overview

The 16-bit real-time counter (RTC) is a counter that typically runs continuously, including in low-power sleep modes, to keep track of time. It can wake up the device from sleep modes and/or interrupt the device at regular intervals.

The reference clock is typically the 1.024kHz output from a high-accuracy crystal of 32.768kHz, and this is the configuration most optimized for low power consumption. The faster 32.768kHz output can be selected if the RTC needs a resolution higher than 1ms. The RTC can also be clocked from an external clock signal, the 32.768kHz internal oscillator or the 32kHz internal ULP oscillator.

The RTC includes a 10-bit programmable prescaler that can scale down the reference clock before it reaches the counter. A wide range of resolutions and time-out periods can be configured. With a 32.768kHz clock source, the maximum resolution is 30.5µs, and time-out periods can range up to 2000 seconds. With a resolution of 1s, the maximum timeout period is more than18 hours (65536 seconds). The RTC can give a compare interrupt and/or event when the counter equals the compare register value, and an overflow interrupt and/or event when it equals the period register value.

Figure 19-1. Real-time Counter Overview



32.1.3 Current Consumption

Table 32-4. Current Consumption for Active Mode and Sleep Modes

Symbol	Parameter	Condition		Min.	Typ.	Max.	Units
I_{CC}	Active power consumption (1)	32kHz, Ext. Clk	V_{CC} = 1.8V		50		µA
			V_{CC} = 3.0V		130		
		1MHz, Ext. Clk	V_{CC} = 1.8V		215		
			V_{CC} = 3.0V		475		
		2MHz, Ext. Clk	V_{CC} = 1.8V		445	600	
			V_{CC} = 3.0V		0.95	1.5	mA
		32MHz, Ext. Clk			7.8	12.0	
	Idle power consumption (1)	32kHz, Ext. Clk	V_{CC} = 1.8V		2.8		µA
			V_{CC} = 3.0V		3		
		1MHz, Ext. Clk	V_{CC} = 1.8V		46		
			V_{CC} = 3.0V		92		
		2MHz, Ext. Clk	V_{CC} = 1.8V		93	225	
			V_{CC} = 3.0V		184	350	
		32MHz, Ext. Clk			2.9	5.0	mA
	Power-down power consumption	T = 25°C	V_{CC} = 3.0V		0.07	1.0	µA
		T = 85°C			1.3	5.0	
		T = 105°C			4.0	8.0	
		WDT and sampled BOD enabled, T = 25°C	V_{CC} = 3.0V		1.3	2.0	
		WDT and sampled BOD enabled, T = 85°C			2.6	6.0	
		WDT and sampled BOD enabled, T= 105°C			5.0	10	
	Power-save power consumption (2)	RTC from ULP clock, WDT and sampled BOD enabled, T = 25°C	V_{CC} = 1.8V		1.7		
			V_{CC} = 3.0V		1.8		
		RTC from 1.024kHz low power 32.768kHz TOSC, T = 25°C	V_{CC} = 1.8V		0.5	2.0	
			V_{CC} = 3.0V		0.7	2.0	
		RTC from low power 32.768kHz TOSC, T = 25°C	V_{CC} = 1.8V		0.9	3.0	
			V_{CC} = 3.0V		1.2	3.0	
	Reset power consumption	Current through $\overline{\text{RESET}}$ pin substracted	V_{CC} = 3.0V		120		

Notes: 1. All Power Reduction Registers set.
2. Maximum limits are based on characterization, and not tested in production.

32.1.4 Wake-up Time from Sleep Modes

Table 32-6. Device Wake-up Time from Sleep Modes with Various System Clock Sources

Symbol	Parameter	Condition	Min.	Typ. (1)	Max.	Units
t_{wakeup}	Wake-up time from idle, standby, and extended standby mode	External 2MHz clock		2.0		µs
		32.768kHz internal oscillator		125		
		2MHz internal oscillator		2.0		
		32MHz internal oscillator		0.2		
	Wake-up time from power-save and power-down mode	External 2MHz clock		4.6		
		32.768kHz internal oscillator		330		
		2MHz internal oscillator		9.5		
		32MHz internal oscillator		5.6		

Note: 1. The wake-up time is the time from the wake-up request is given until the peripheral clock is available on pin, see Figure 32-2. All peripherals and modules start execution from the first clock cycle, expect the CPU that is halted for four clock cycles before program execution starts.

Figure 32-2. Wake-up Time Definition

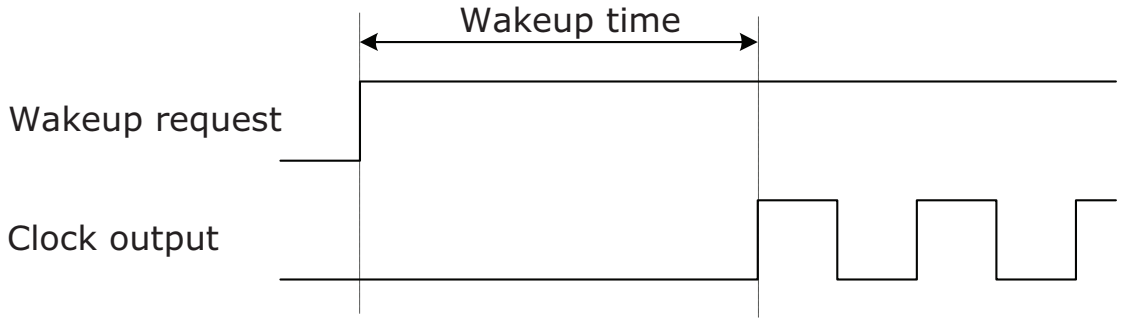


Table 32-69. Gain Stage Characteristics

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
R_{in}	Input resistance	Switched in normal mode		4.0		kΩ
C_{sample}	Input capacitance	Switched in normal mode		4.4		pF
	Signal range	Gain stage output	0		AV_{CC} - 0.6	V
	Propagation delay	ADC conversion rate	1/2	1	3	Clk_{ADC} cycles
	Clock frequency	Same as ADC	100		1800	kHz
	Gain error	0.5x gain, normal mode		-1		%
		1x gain, normal mode		-1		
		8x gain, normal mode		-1		
		64x gain, normal mode		5		
	Offset error, input referred	0.5x gain, normal mode		10		mV
		1x gain, normal mode		5		
		8x gain, normal mode		-20		
		64x gain, normal mode		-126		

32.3.7 Analog Comparator Characteristics

Table 32-70. Analog Comparator Characteristics

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
V_{off}	Input offset voltage			10		mV
I_{lk}	Input leakage current			<10	50	nA
	Input voltage range		-0.1		AV_{CC}	V
	AC startup time			50		µs
V_{hys1}	Hysteresis, none	V_{CC} = 1.6V - 3.6V		0		mV
V_{hys2}	Hysteresis, small	V_{CC} = 1.6V - 3.6V		15		
V_{hys3}	Hysteresis, large	V_{CC} = 1.6V - 3.6V		30		
t_{delay}	Propagation delay	V_{CC} = 3.0V, T = 85°C		20	90	ns
		V_{CC} = 3.0V		17		
	64-level voltage scaler	Integral non-linearity (INL)		0.3	0.5	lsb
	Current source accuracy after calibration			5		%
	Current source calibration range	Single mode	4		6	µA

32.6.11 Power-on Reset Characteristics

Table 32-161. Power-on Reset Characteristics

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
V_{POT-} (1)	POR threshold voltage falling V_{CC}	V_{CC} falls faster than 1V/ms	0.4	1.0		V
		V_{CC} falls at 1V/ms or slower	0.8	1.3		
V_{POT+}	POR threshold voltage rising V_{CC}			1.3	1.59	

Note: 1. V_{POT-} values are only valid when BOD is disabled. When BOD is enabled $V_{POT-} = V_{POT+}$.

32.6.12 Flash and EEPROM Memory Characteristics

Table 32-162. Endurance and Data Retention

Symbol	Parameter	Condition		Min.	Typ.	Max.	Units
	Flash	Write/Erase cycles	25°C	10K			Cycle
			85°C	10K			
			105°C	2K			
		Data retention	25°C	100			Year
			85°C	25			
			105°C	10			
	EEPROM	Write/Erase cycles	25°C	100K			Cycle
			85°C	100K			
			105°C	30K			
		Data retention	25°C	100			Year
			85°C	25			
			105°C	10			

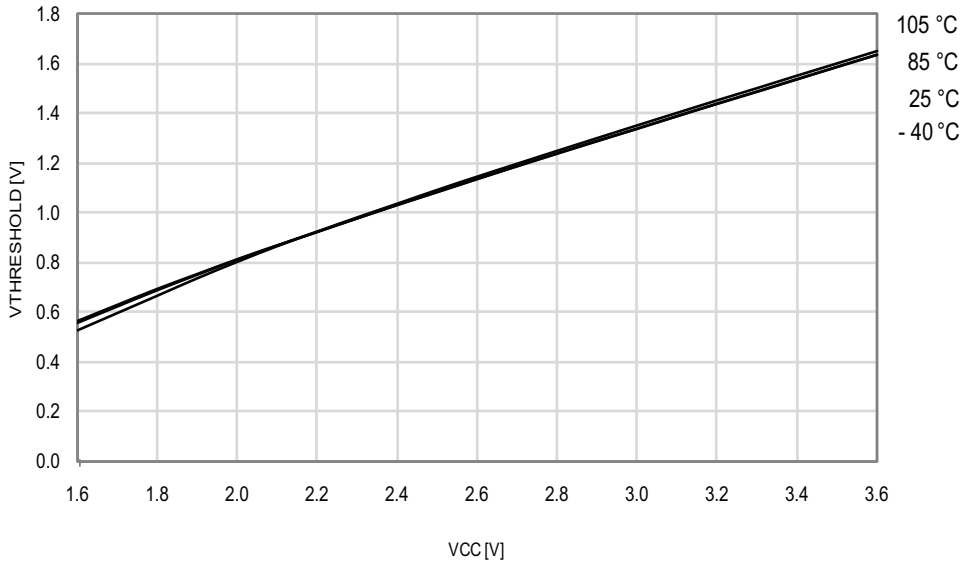
Table 32-163. Programming Time

Symbol	Parameter	Condition	Min.	Typ. (1)	Max.	Units
	Chip erase (2)	384KB Flash, EEPROM		130		ms
	Application erase	Section erase		6		
	Flash	Page erase		6		
		Page write		6		
		Atomic page erase and write		12		
	EEPROM	Page erase		6		
		Page write		6		
		Atomic page erase and write		12		

Notes: 1. Programming is timed from the 2MHz internal oscillator.
2. EEPROM is not erased if the EESAVE fuse is programmed.

Figure 33-124. Reset Pin Input Threshold Voltage vs. V_{CC}

V_{IH} - Reset pin read as "1"



33.2.8 Oscillator Characteristics

33.2.8.1 Ultra Low-Power Internal Oscillator

Figure 33-125. Ultra Low-Power Internal Oscillator Frequency vs. Temperature

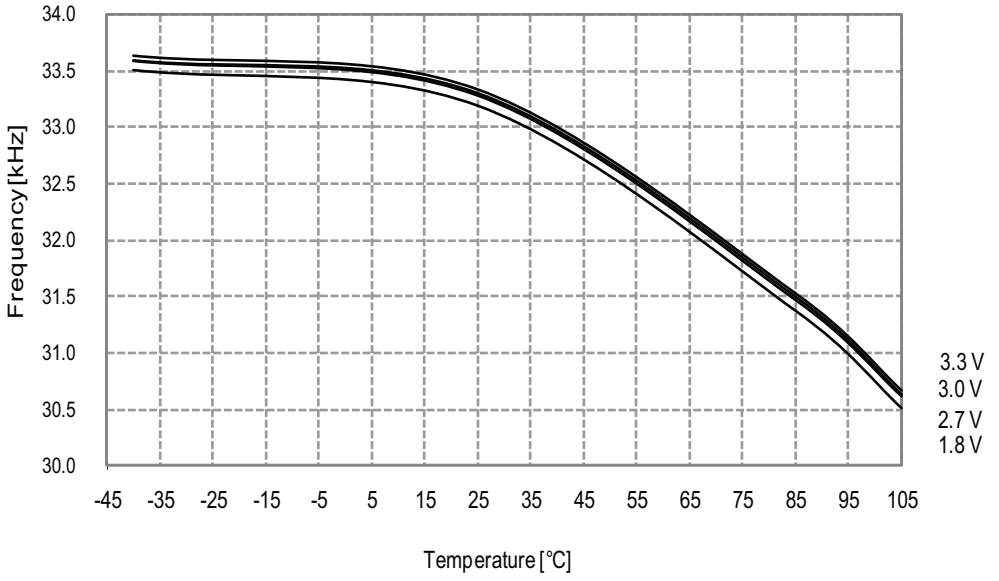


Figure 33-155. Idle Mode Supply Current vs. V_{CC}

f_{SYS} = 32MHz internal oscillator prescaled to 8MHz

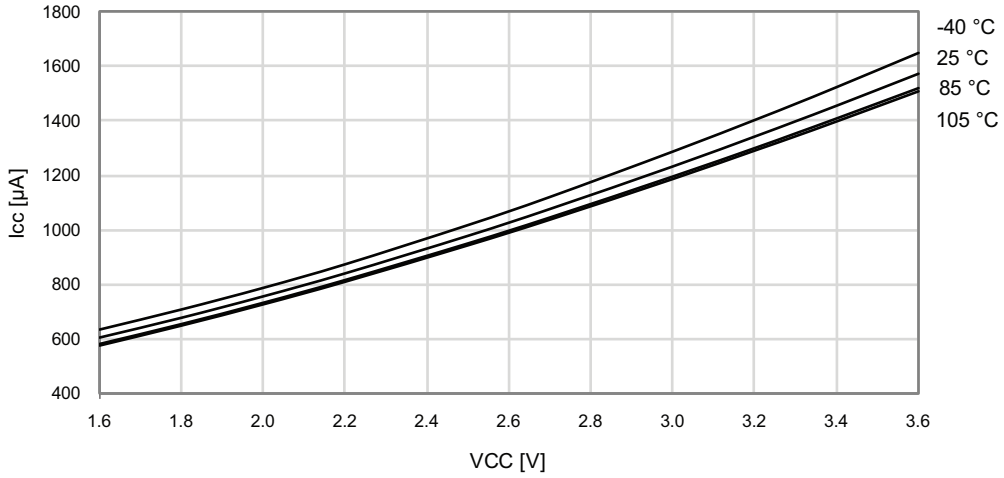
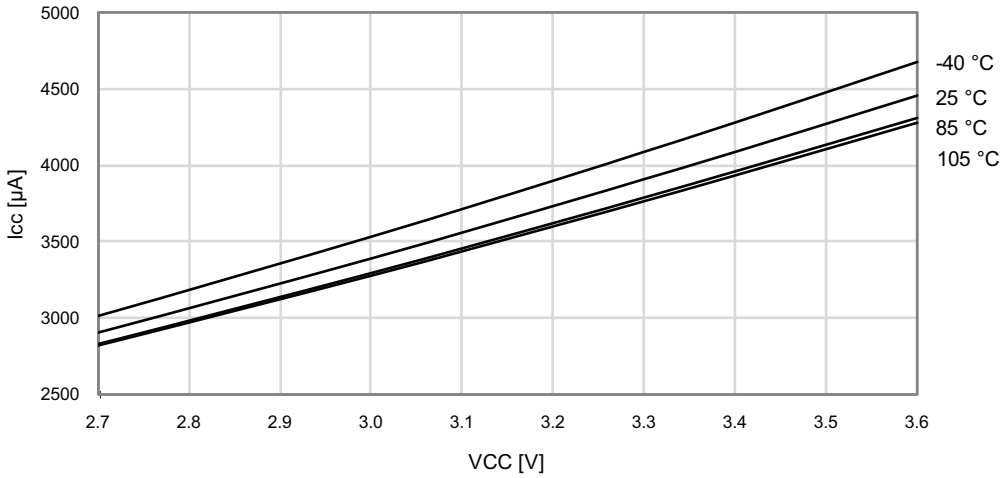


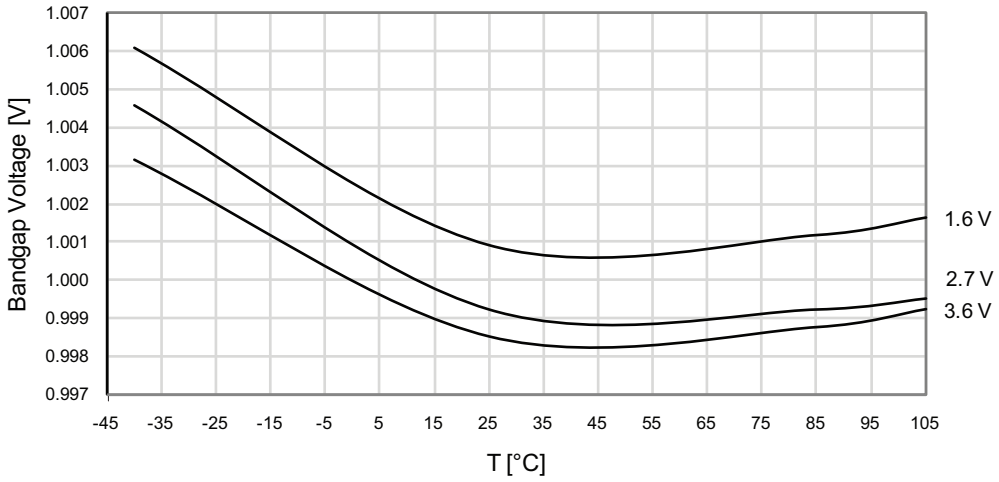
Figure 33-156. Idle Mode Current vs. V_{CC}

f_{SYS} = 32MHz internal oscillator



33.4.5 Internal 1.0V Reference Characteristics

Figure 33-257.ADC Internal 1.0V Reference vs. Temperature



33.4.6 BOD Characteristics

Figure 33-258.BOD Thresholds vs. Temperature

BOD level = 1.6V

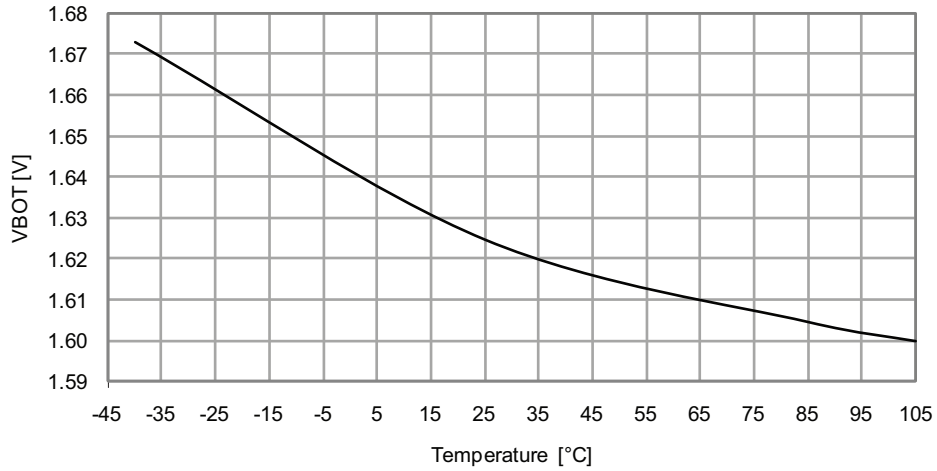


Figure 33-275. 32MHz Internal Oscillator CALA Calibration Step Size

T = 85°C, V_{CC} = 3.0V

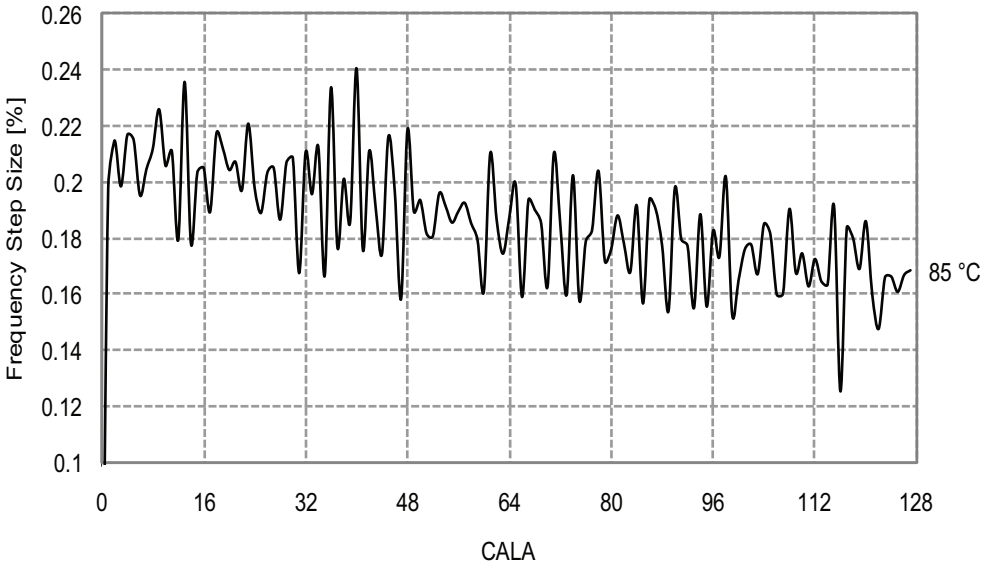
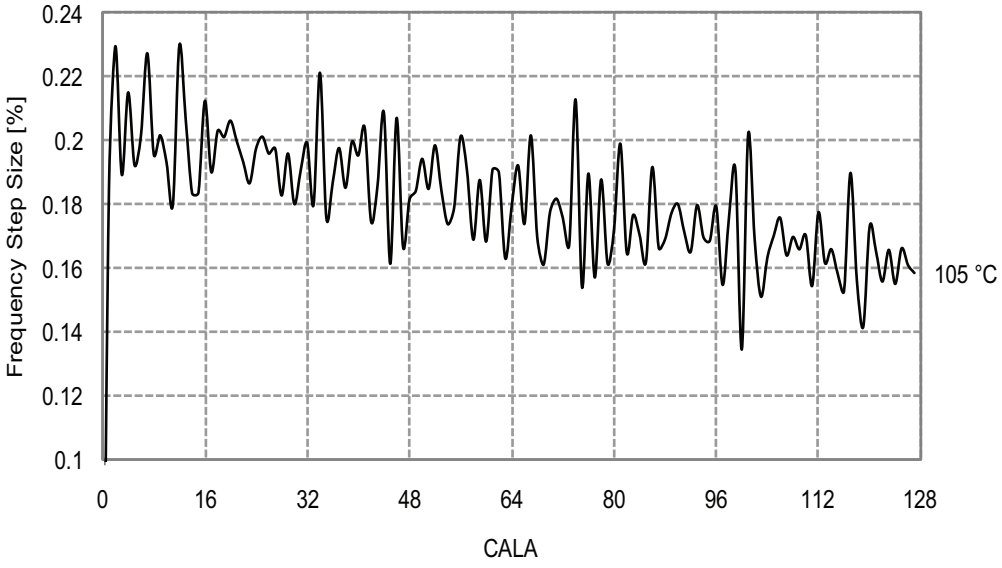


Figure 33-276. 32MHz Internal Oscillator CALA Calibration Step Size

T = 105°C, V_{CC} = 3.0V



33.5 Atmel ATxmega256D3

33.5.1 Current Consumption

33.5.1.1 Active Mode Supply Current

Figure 33-283.Active Supply Current vs. Frequency

f_{SYS} = 0 - 1MHz external clock, T = 25°C

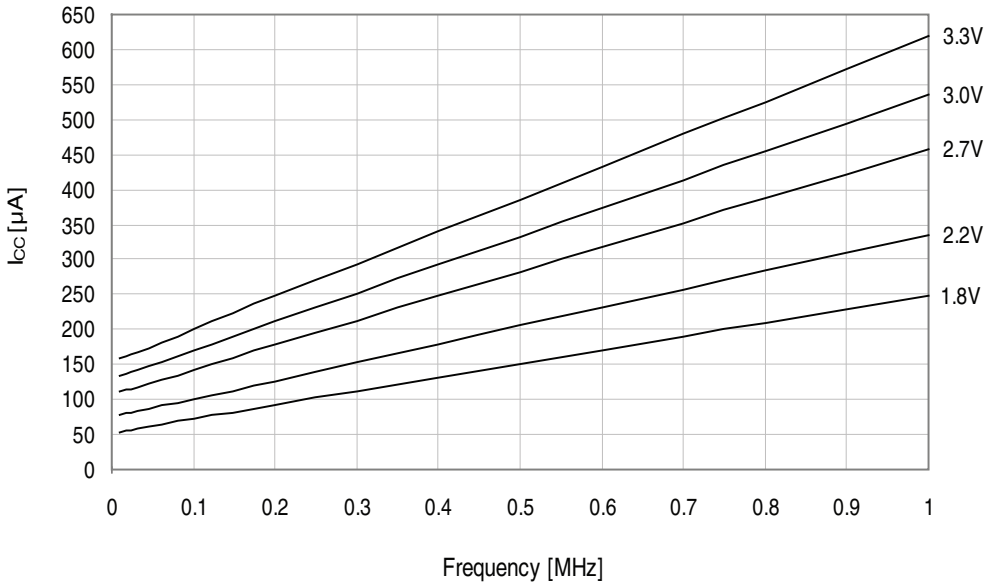
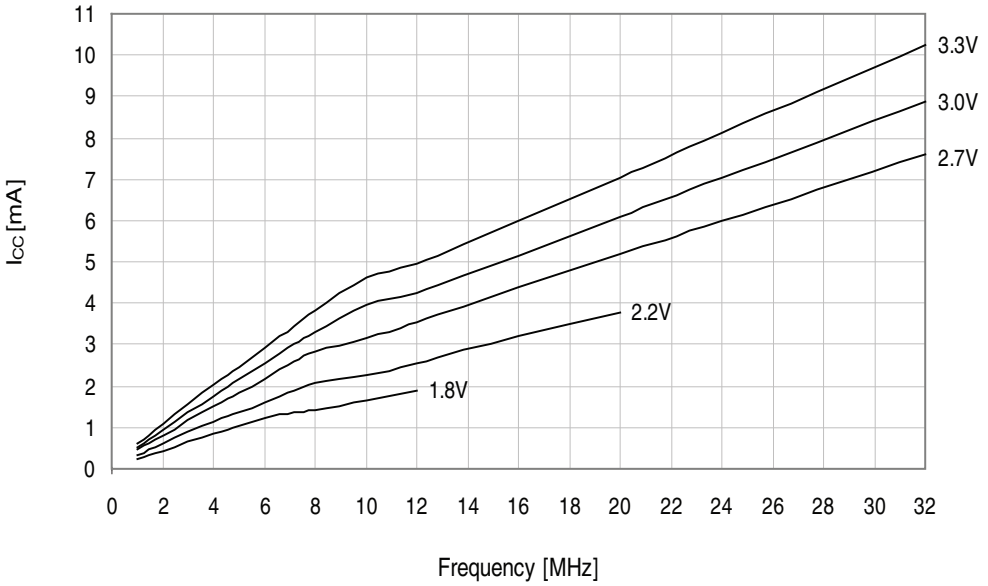


Figure 33-284.Active Supply Current vs. Frequency

f_{SYS} = 1 - 32MHz external clock, T = 25°C



33.5.2.2 Output Voltage vs. Sink/Source Current

Figure 33-303.I/O Pin Output Voltage vs. Source Current

V_{CC} = *1.8V*

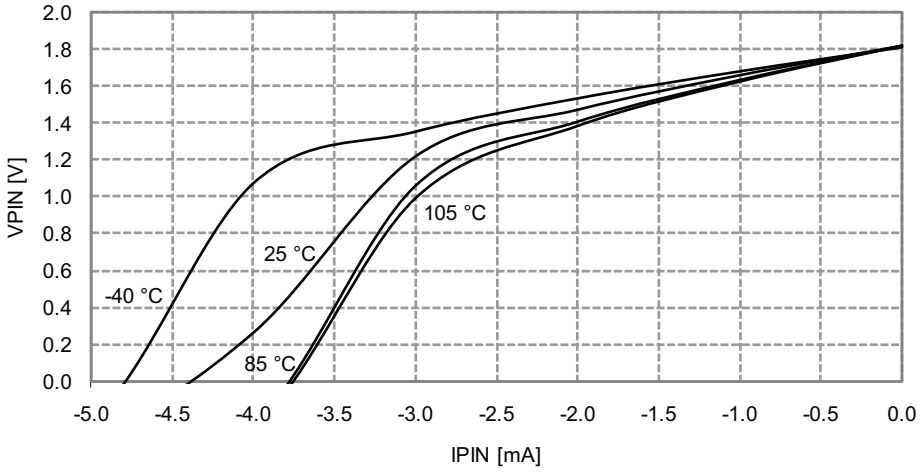


Figure 33-304.I/O Pin Output Voltage vs. Source Current

V_{CC} = *3.0V*

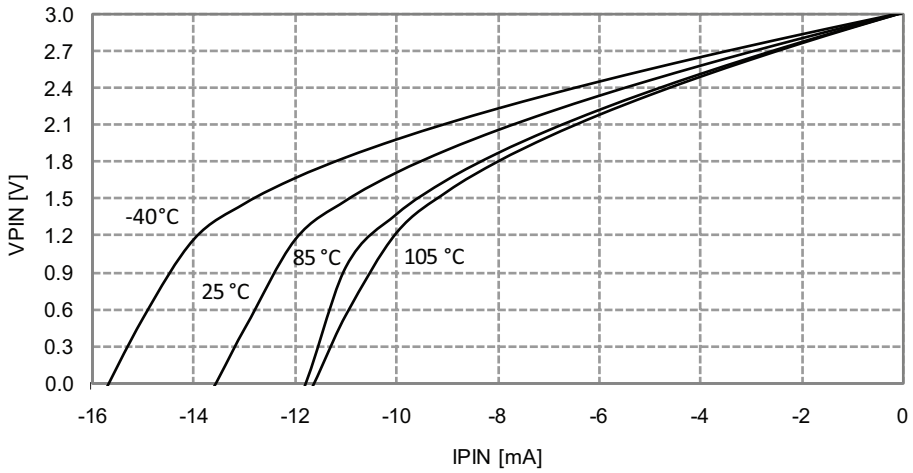


Figure 33-317.DNL Error vs. Input Code

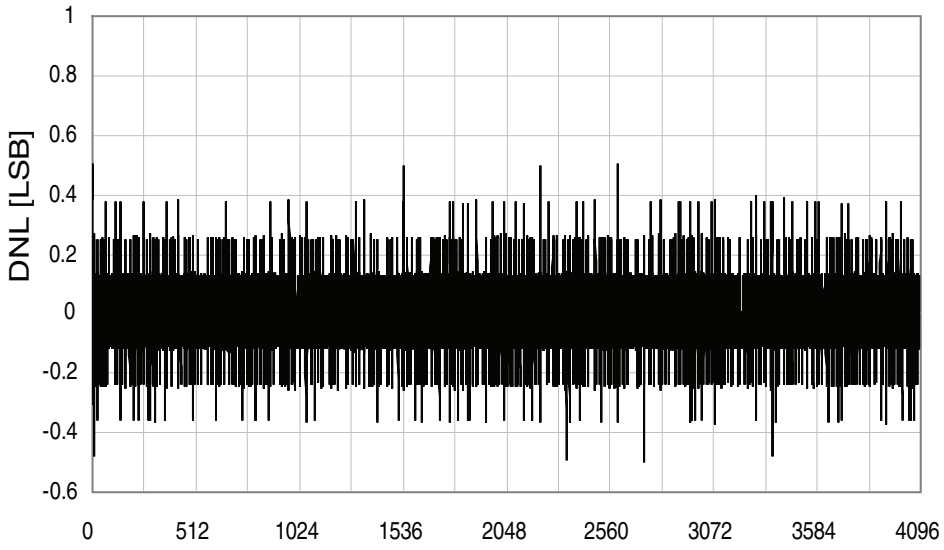
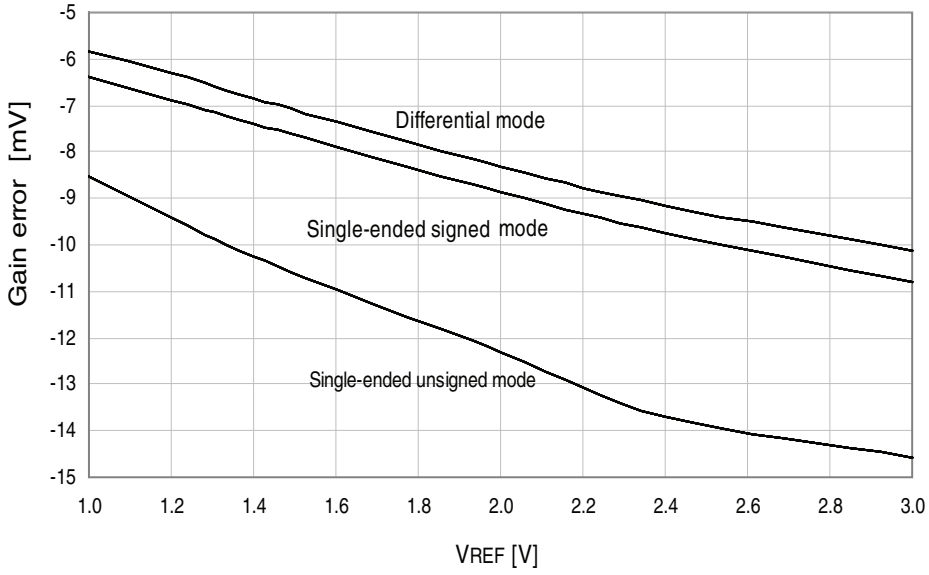


Figure 33-318.Gain Error vs. V_{REF}

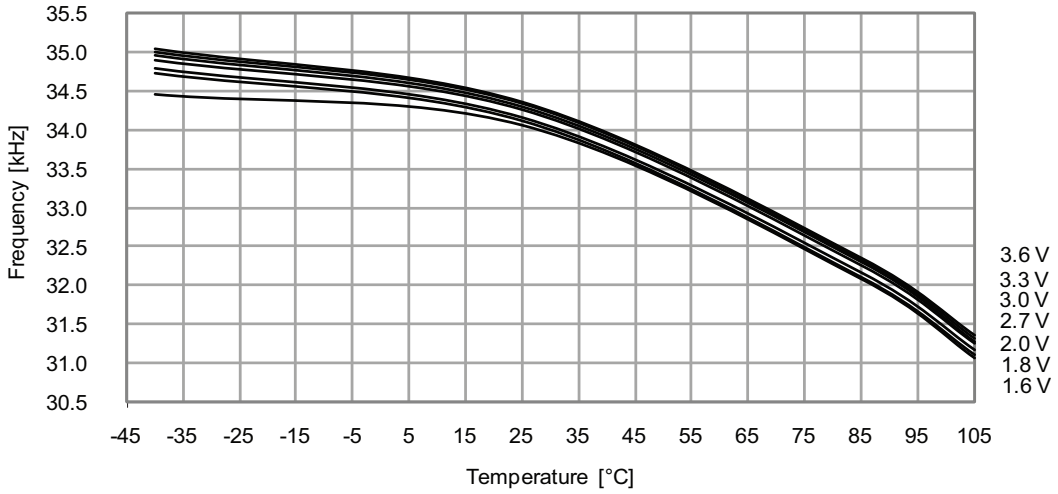
T = 25°C, V_{CC} = 3.6V, ADC sample rate = 300ksps



33.5.8 Oscillator Characteristics

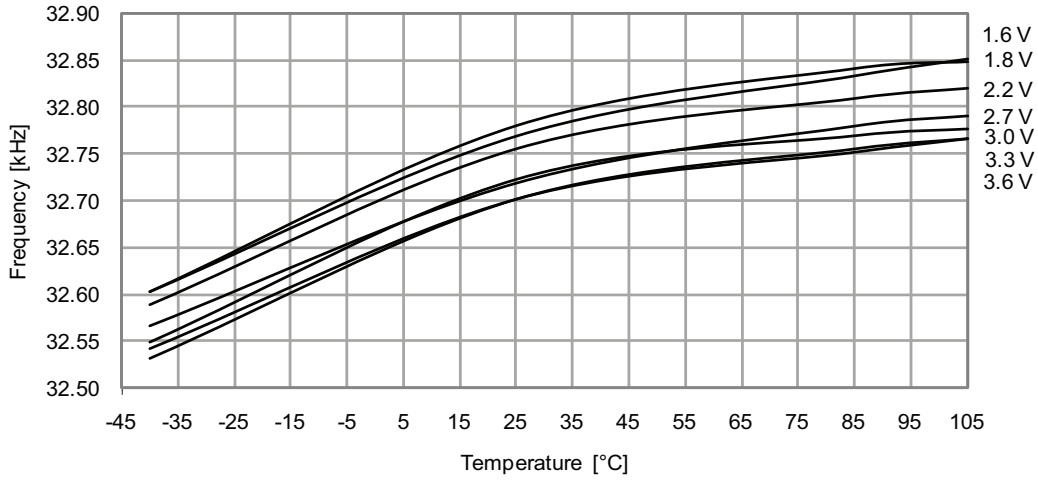
33.5.8.1 Ultra Low-Power Internal Oscillator

Figure 33-335. Ultra Low-Power Internal Oscillator Frequency vs. Temperature



33.5.8.2 32.768kHz Internal Oscillator

Figure 33-336. 32.768kHz Internal Oscillator Frequency vs. Temperature



33.5.8.4 32MHz Internal Oscillator

Figure 33-341. 32MHz Internal Oscillator Frequency vs. Temperature

DFLL disabled

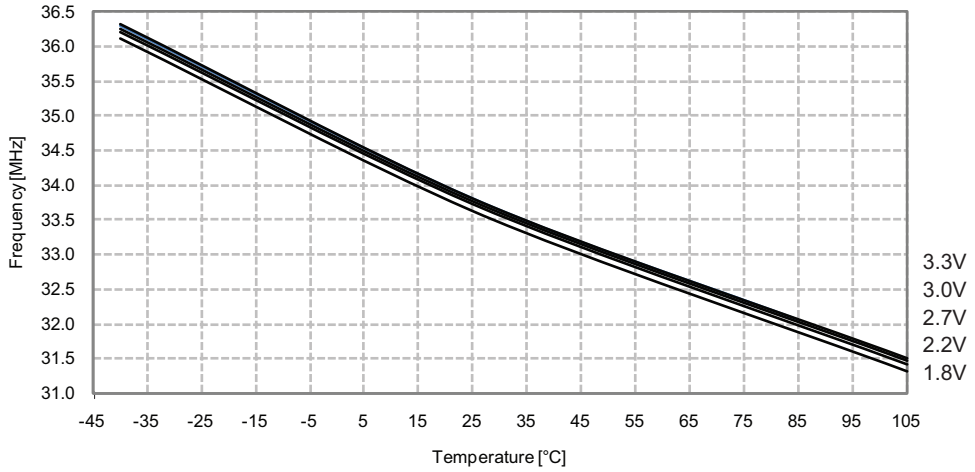
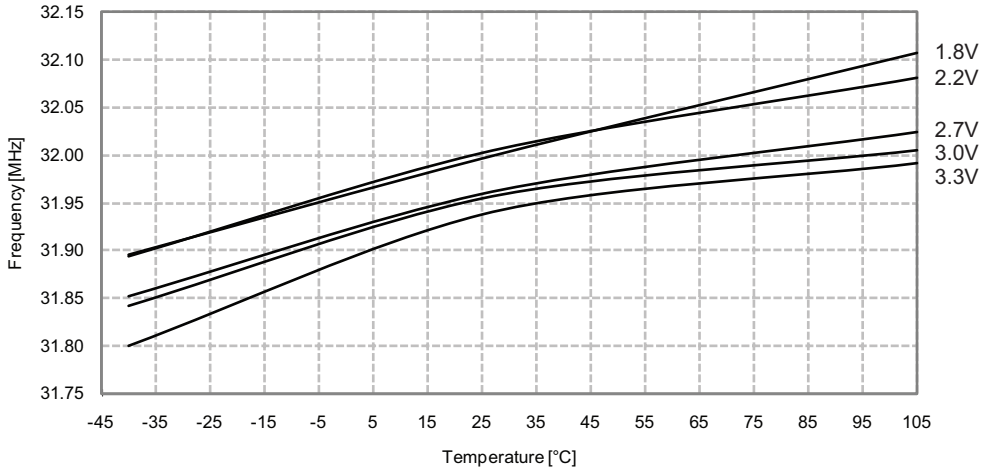


Figure 33-342. 32MHz Internal Oscillator Frequency vs. Temperature

DFLL enabled, from the 32.768kHz internal oscillator



33.6.4 Analog Comparator Characteristics

Figure 33-393. Analog Comparator Hysteresis vs. V_{CC}

Small hysteresis

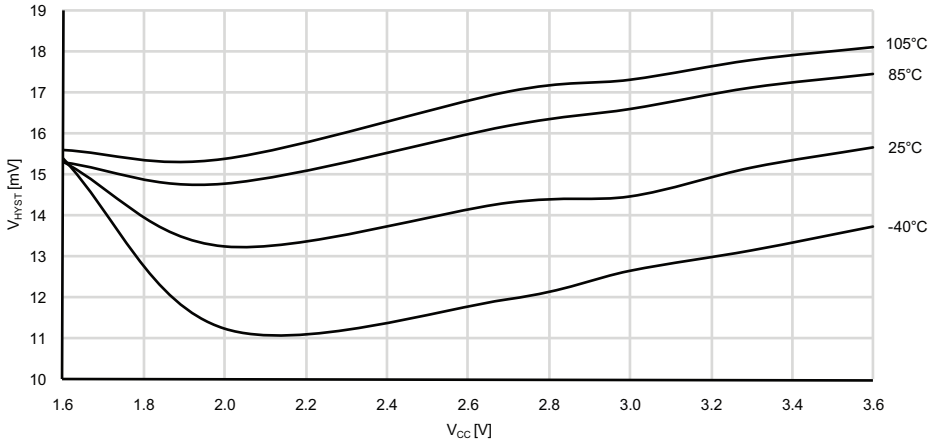
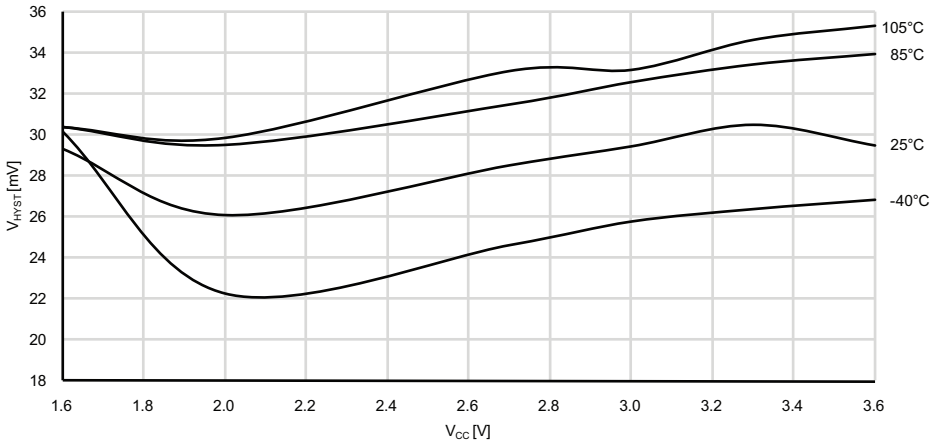


Figure 33-394. Analog Comparator Hysteresis vs. V_{CC}

Large hysteresis



Problem fix/workaround

Check if the bus state is IDLE. If this is the case, it is safe to clear APIF. If the bus state is not IDLE, wait for the SCL pin to be low before clearing APIF.

Code:

```
/* Only clear the interrupt flag if within a "safe zone". */
while ( /* Bus not IDLE: */
       ((COMMS_TWI.MASTER.STATUS & TWI_MASTER_BUSSTATE_gm) !=
         TWI_MASTER_BUSSTATE_IDLE_gc)) &&
         /* SCL not held by slave: */
         !(COMMS_TWI.SLAVE.STATUS & TWI_SLAVE_CLKHOLD_bm)
      )
{
    /* Ensure that the SCL line is low */
    if ( !(COMMS_PORT.IN & PIN1_bm) )
        if ( !(COMMS_PORT.IN & PIN1_bm) )
            break;
}
/* Check for an pending address match interrupt */
if ( !(COMMS_TWI.SLAVE.STATUS & TWI_SLAVE_CLKHOLD_bm) )
{
    /* Safely clear interrupt flag */
    COMMS_TWI.SLAVE.STATUS |= (uint8_t)TWI_SLAVE_APIF_bm;
}
```

22. TWI START condition at bus timeout will cause transaction to be dropped

If Bus Timeout is enabled and a timeout occurs on the same Peripheral Clock cycle as a START is detected, the transaction will be dropped.

Problem fix/workaround

None.

23. TWI Data Interrupt Flag erroneously read as set

When issuing the TWI slave response command CMD=0b11, it takes one Peripheral Clock cycle to clear the data interrupt flag (DIF). A read of DIF directly after issuing the command will show the DIF still set.

Problem fix/workaround

Add one NOP instruction before checking DIF.

24. WDR instruction inside closed window will not issue reset

When a WDR instruction is execute within one ULP clock cycle after updating the window control register, the counter can be cleared without giving a system reset.

Problem fix/workaround

Wait at least one ULP clock cycle before executing a WDR instruction.

25. Non available functions and options

The below function and options are not available. Writing to any registers or fuse to try and enable or configure these functions or options will have no effect, and will be as writing to a reserved address location.

- TWIE, the TWI module on PORTE
- TWI SDAHOLD option in the TWI CTRL register is one bit

34.4.8 Rev. B

- Bandgap voltage input for the ACs can not be changed when used for both ACs simultaneously
- VCC voltage scaler for AC is non-linear
- ADC gain stage cannot be used for single conversion
- ADC has increased INL error for some operating conditions
- ADC gain stage output range is limited to 2.4V
- ADC Event on compare match non-functional
- ADC propagation delay is not correct when 8× – 64× gain is used
- Bandgap measurement with the ADC is non-functional when VCC is below 2.7V
- Accuracy lost on first three samples after switching input to ADC gain stage
- Configuration of PGM and CWCM not as described in the XMEGA D Manual
- PWM is not restarted properly after a fault in cycle-by-cycle mode
- BOD will be enabled at any reset
- EEPROM page buffer always written when NVM DATA0 is written
- Pending full asynchronous pin change interrupts will not wake the device
- Pin configuration does not affect Analog Comparator Output
- NMI Flag for Crystal Oscillator Failure automatically cleared
- Writing EEPROM or Flash while reading any of them will not work
- RTC Counter value not correctly read after sleep
- Pending asynchronous RTC-interrupts will not wake up device
- TWI Transmit collision flag not cleared on repeated start
- Clearing TWI Stop Interrupt Flag may lock the bus
- TWI START condition at bus timeout will cause transaction to be dropped
- TWI Data Interrupt Flag (DIF) erroneously read as set
- WDR instruction inside closed window will not issue reset
- Non available functions and options
- Sampled BOD in Active mode will cause noise when bandgap is used as reference
- Temperature sensor not calibrated

1. Bandgap voltage input for the ACs cannot be changed when used for both ACs simultaneously

If the Bandgap voltage is selected as input for one Analog Comparator (AC) and then selected/deselected as input for another AC, the first comparator will be affected for up to 1µs and could potentially give a wrong comparison result.

Problem fix/workaround

If the Bandgap is required for both ACs simultaneously, configure the input selection for both ACs before enabling any of them.

2. VCC voltage scaler for AC is non-linear

The 6-bit VCC voltage scaler in the Analog Comparators is non-linear.

34.5.5 Rev. E

- Bandgap voltage input for the ACs can not be changed when used for both ACs simultaneously
- V_{CC} voltage scaler for AC is non-linear
- ADC gain stage cannot be used for single conversion
- ADC has increased INL error for some operating conditions
- ADC gain stage output range is limited to 2.4V
- ADC Event on compare match non-functional
- ADC propagation delay is not correct when 8× – 64× gain is used
- Bandgap measurement with the ADC is non-functional when V_{CC} is below 2.7V
- Accuracy lost on first three samples after switching input to ADC gain stage
- Configuration of PGM and CWCM not as described in the XMEGA D Manual
- PWM is not restarted properly after a fault in cycle-by-cycle mode
- BOD will be enabled at any reset
- EEPROM page buffer always written when NVM DATA0 is written
- Pending full asynchronous pin change interrupts will not wake the device
- Pin configuration does not affect Analog Comparator Output
- NMI Flag for Crystal Oscillator Failure automatically cleared
- RTC Counter value not correctly read after sleep
- Pending asynchronous RTC-interrupts will not wake up device
- TWI Transmit collision flag not cleared on repeated start
- Clearing TWI Stop Interrupt Flag may lock the bus
- TWI START condition at bus timeout will cause transaction to be dropped
- TWI Data Interrupt Flag (DIF) erroneously read as set
- WDR instruction inside closed window will not issue reset
- Non available functions and options
- Sampled BOD in Active mode will cause noise when bandgap is used as reference
- Temperature sensor not calibrated
- Disabling the USART transmitter does not automatically set the TxD pin direction to input

1. Bandgap voltage input for the ACs cannot be changed when used for both ACs simultaneously

If the Bandgap voltage is selected as input for one Analog Comparator (AC) and then selected/deselected as input for another AC, the first comparator will be affected for up to 1µs and could potentially give a wrong comparison result.

Problem fix/workaround

If the Bandgap is required for both ACs simultaneously, configure the input selection for both ACs before enabling any of them.

2. V_{CC} voltage scaler for AC is non-linear

The 6-bit V_{CC} voltage scaler in the Analog Comparators is non-linear.

Atmel Corporation 1600 Technology Drive, San Jose, CA 95110 USA **T:** (+1)(408) 441.0311 **F:** (+1)(408) 436.4200 | **www.atmel.com**